

# Analysis of PCB Irradiation Tests



Roman Pöschl LAL Orsay

- Motivation
- Experimental Setup
- Data Samples
- Analysis and Results
- Summary, Conclusion and Outlook

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# Introduction

Calorimeter Electronics to be interleaved with layer structure



Do high energetic showers create signals directly in electronics ? If yes, Rate of faked signals ?

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Special PCB in Ecal Prototype during CERN 07 testbeam – Experimental Setup I



**Prepared Slab** 

- W dummy

- capton and paper for electrical shielding

**Usual Slab** 

Special PCB in Ecal Prototype during CERN 07 testbeam – Experimental Setup II

- PCB positioned at place of layer 12 in Ecal  $\sim$  shower maximum x,y position identical to layer 2
- Schematic view of test PCB 'Expect' signals from 72 pads, 4x18 = 2 Wafer



- 2.6 10<sup>6</sup> Events with 90 GeV Electrons (- 5.8 10<sup>5</sup> with 70 GeV Electrons) At least 70 K at each scanning point (Details see later) Runs 331462 – 331518 Today: Analysis of 10k Events per analysed run (nearly) Full Statistics
- First Step: Runs were subject to the same data processing chain as 'usual' runs Calice Collaboration Meeting Feb. 2009

First Steps of Data Analysis – Alignment Studies

Beam Impact at nominal center of Chip 1 (-8.33,0) cm



70 GeV e- - Beam Impact at nominal center of Chip 1 (-8.33,0) cm Layer\_12\_hist Layer 13 hist 18E 2.5 Ghost Hit? 16 Hits 1.5 Layer 12 0.5 Layer\_14\_hist Layer\_15\_hist 18 F 18 F Projection of Center of Chip1 onto layer 14 \_\_\_\_2000 - Chip 1 well 'touched' by shower maximum eb. 2009 - Small Activity in Layer 12

First Steps of Data Analysis – Rough Alignment Studies

### Basic Spectra (for 10k Events)







# Basic Spectra (10k Events)



So far all runs have been reconstruction using usual reco software

Now

Discarding all (Offline) Pedestal Corrections

- Methodology:

Subdivision of Runs into BeamTrigger and Pedestal Trigger Events (Oscillator Trigger) interleaved with beam events

Expectation no difference between spectra in the both cases

# **Statistics of Analysis**



On Run Selection and Observations

- Run Selected according to entries in the logbook No comments on bad quality by Shift Crew
- Switch of energy between Run 331473 and Run 331478

Change in Pedestal Rate
20% of all events -> 5% of all events
Still at least 3500 of (valuable) pedestal events

# - at least 70 at each point

- ... but Run 331471 poor statistics 10k (can be increased by using 331470) very first scanning point
- mostly 90 kEvents for off center runs
- > 200k at (nomincal) Chip Center

Noise Spectra Scan 1

Scan ID

# Signal Events Pedestal Events





# **Discussion of Noise Spectra**

Disclaimer will show only a selection of plots

- Full set of scan plots in Annex to talk
- First Order: No difference between signal and pedestal events visible
- Signal looks slightly shifted w.r.t pure Pedestal events Larger tails Number of Hits above MIP threshold O(10<sup>-5</sup>)
- No obvious dependency on scan position
- Next step Test "gaussianess" of a signal

Expectation: Pedestal events should lead to pure Gaussian noise distribution Method: Determine  $\chi^2$ /ndf for different fit ranges Fit Ranges: (-4,4), (-8,8), (-12,12), (-16,16) ADC Counts

#### "Gaussianness" in Scan 1

#### Signal/5 ADC Counts **Pedestal**



"Gaussianness" in Scan 2

#### Signal/5 ADC Counts **Pedestal**



"Gaussianness" in Scan 3

#### Signal/5 ADC Counts Pedestal



"Gaussianness" in Scan 4

#### Signal/5 ADC Counts **Pedestal**



Discussion of Gaussian Behaviour of Noise Spectra

#### - Clear tendency observed

Noise spectra in Layer 12 much less gaussian in Signal Events than in Pedestal events Average  $\chi^2$ /ndf in Pedestal events ~3 Remember  $\chi^2$ /ndf for Signal Events has been divided by 5

But ... no dependency on scan position visible!!!

 Chips are obiously sensitive to activity in detector when energy is deposited
Small Insulation problem?

 Next step: Quantify global changes between signal and pedestal events
Back to mean and rms as gaussian is maybe not a meaningful quantity

# Average Mean and RMS for Scan 1



No dependency on scan position visible

## Average Mean and RMS for Scan 2



No dependency on scan position visible

# Average Mean and RMS for Scan 3



No dependency on scan position visible





No dependency on scan position visible

Summary, Conclusion and Outlook

- Analysis of PCB Irradiation test extended to (nearly) full statistics
- #Events beyond 1 MIP appear at O(10<sup>-5</sup>)

# No evidence that shower particles create fake hits in detector

- Energy deposit in detector distorts the gaussian noise spectrum
  - Small sensitivity to detector load, Floating currents etc.
  - Let usual noise very rarely fluctuate above MIP threshold (45 ADC Counts)
- Global effect of parisitic signals (whereever they come from) is O(1% of a MIP) on the average signal and not measurable in the width i.e. rms of the detector noise (Which is also good news for all other SiW Ecal Analyses)

# - All observed effects seem to be independent of scan position

- Plan to report presented results as contributed paper to TIPP09
- Paper for NIM should be accompanied by a simulation study First ideas exchanged with Christoph

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# Annex: Noise Spectra















